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HEF4040B

12-stage binary ripple counter Rev. 9 — 23 March 2016

Product data sheet

1. **General description**

The HEF4040B is a 12-stage binary ripple counter with a clock input (CP), an overriding asynchronous master reset input (MR) and twelve fully buffered outputs (Q0 to Q11). The counter advances on the HIGH-to-LOW transition of $\overline{\text{CP}}$. A HIGH on MR clears all counter stages and forces all outputs LOW, independent of CP. Each counter stage is a static toggle flip-flop. The clock input is highly tolerant of slow rise and fall times due to its Schmitt trigger action.

It operates over a recommended V_{DD} power supply range of 3 V to 15 V referenced to V_{SS} (usually ground). Unused inputs must be connected to V_{DD} , V_{SS} , or another input.

2. Features and benefits

- Tolerant of slow clock rise and fall time
- Fully static operation
- 5 V, 10 V, and 15 V parametric ratings
- Standardized symmetrical output characteristics
- Specified from –40 °C to +85 °C
- Complies with JEDEC standard JESD 13-B

3. Applications

- Frequency dividing circuits
- Time delay circuits
- Control counters

Ordering information

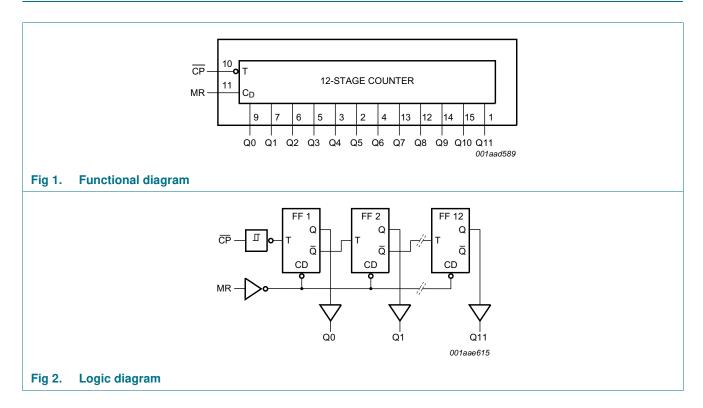
Table 1. **Ordering information**

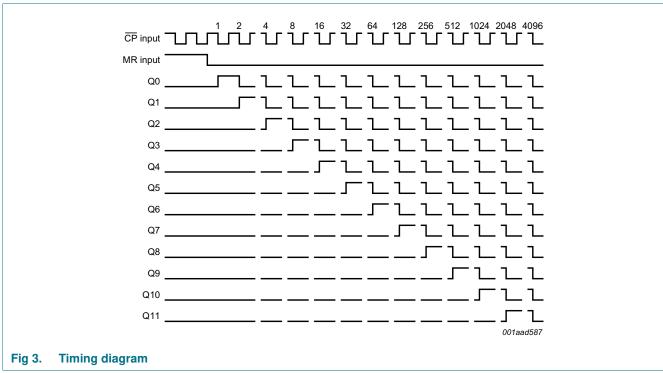
All types operate from $-40 \,^{\circ}\text{C}$ to $+85 \,^{\circ}\text{C}$.

Type number	Package							
	Name	Description	Version					
HEF4040BT	SO16	plastic small outline package; 16 leads; body width 3.9 mm	SOT109-1					



Functional diagram

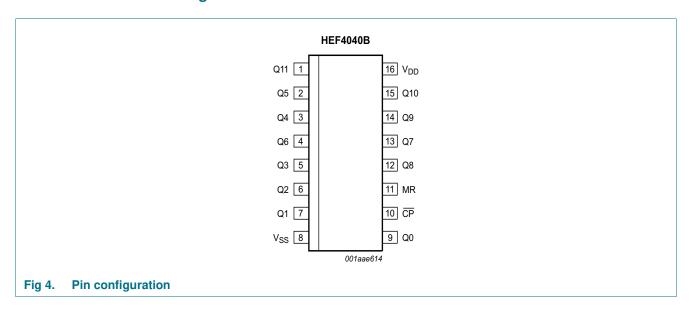






6. Pinning information

6.1 Pinning



6.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
V_{SS}	8	ground supply voltage
Q0 to Q11	9, 7, 6, 5, 3, 2, 4, 13, 12, 14, 15, 1	parallel output
CP	10	clock input (HIGH-to-LOW edge-triggered)
MR	11	master reset input (active HIGH)
V_{DD}	16	supply voltage

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7. Limiting values

Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DD}	supply voltage		-0.5	+18	V
l _{iK}	input clamping current	$V_{I} < -0.5 \text{ V or } V_{I} > V_{DD} + 0.5 \text{ V}$	-	±10	mA
VI	input voltage		-0.5	$V_{DD} + 0.5$	V
l _{OK}	output clamping current	$V_{O} < -0.5 \text{ V or } V_{O} > V_{DD} + 0.5 \text{ V}$	-	±10	mA
I _{I/O}	input/output current		-	±10	mA
I _{DD}	supply current		-	50	mA
T _{stg}	storage temperature		-65	+150	°C
T _{amb}	ambient temperature		-40	+85	°C
P _{tot}	total power dissipation	SO16 package	-	500	mW
Р	power dissipation	per output	-	100	mW

^[1] For SO16 package: Ptot derates linearly with 8 mW/K above 70 °C.

8. Recommended operating conditions

Table 4. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DD}	supply voltage		3	-	15	V
V _I	input voltage		0	-	V_{DD}	V
T _{amb}	ambient temperature	in free air	-40	-	+85	°C
Δt/ΔV	input transition rise and fall rate	$V_{DD} = 5 V$	-	-	3.75	ms/V
		V _{DD} = 10 V	-	-	0.5	ms/V
		V _{DD} = 15 V	-	-	0.08	ms/V

9. Static characteristics

Table 5. Static characteristics

 $V_{SS} = 0 \ V$; $V_{I} = V_{SS}$ or V_{DD} ; unless otherwise specified.

Symbol	Parameter	Conditions	V_{DD}	T _{amb} =	T _{amb} = -40 °C		T _{amb} = 25 °C		T _{amb} = 85 °C	
				Min	Max	Min	Max	Min	Max	
V_{IH}	HIGH-level input voltage	$ I_O < 1 \mu A$	5 V	3.5	-	3.5	-	3.5	-	٧
			10 V	7.0	-	7.0	-	7.0	-	٧
			15 V	11.0	-	11.0	-	11.0	-	٧
V_{IL}	LOW-level input voltage	$ I_O < 1 \mu A$	5 V	-	1.5	-	1.5	-	1.5	٧
			10 V	-	3.0	-	3.0	-	3.0	٧
			15 V	-	4.0	-	4.0	-	4.0	٧
V_{OH}	HIGH-level output voltage	$ I_O < 1 \mu A$	5 V	4.95	-	4.95	-	4.95	-	٧
			10 V	9.95	-	9.95	-	9.95	-	٧
			15 V	14.95	-	14.95	-	14.95	-	V

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 Table 5.
 Static characteristics ...continued

 $V_{SS} = 0 \ V$; $V_{I} = V_{SS}$ or V_{DD} ; unless otherwise specified.

Symbol	Parameter	Conditions	V_{DD}	T _{amb} =	–40 °C	T _{amb} = 25 °C		T _{amb} = 85 °C		Unit
				Min	Max	Min	Max	Min	Max	
V_{OL}	LOW-level output voltage	$ I_{O} < 1 \mu A$	5 V	-	0.05	-	0.05	-	0.05	٧
			10 V	-	0.05	-	0.05	-	0.05	٧
			15 V	-	0.05	-	0.05	-	0.05	٧
I _{OH}	HIGH-level output current	$V_0 = 2.5 \text{ V}$	5 V	-	-1.7	-	-1.4	-	-1.1	mA
		$V_{O} = 4.6 \text{ V}$	5 V	-	-0.52	-	-0.44	-	-0.36	mA
		$V_{O} = 9.5 \text{ V}$	10 V	-	-1.3	-	-1.1	-	-0.9	mA
		$V_{O} = 13.5 \text{ V}$	15 V	-	-3.6	-	-3.0	-	-2.4	mA
I _{OL}	LOW-level output current	$V_{O} = 0.4 \text{ V}$	5 V	0.52	-	0.44	-	0.36	-	mA
		$V_{O} = 0.5 \text{ V}$	10 V	1.3	-	1.1	-	0.9	-	mA
		V _O = 1.5 V	15 V	3.6	-	3.0	-	2.4	-	mA
ILI	input leakage current		15 V	-	±0.3	-	±0.3	-	±1.0	μΑ
I _{DD}	supply current	I _O = 0 A	5 V	-	20	-	20	-	150	μΑ
			10 V	-	40	-	40	-	300	μΑ
			15 V	-	80	-	80	-	600	μΑ
Cı	input capacitance		-	-	-	-	7.5	-	-	pF

10. Dynamic characteristics

Table 6. Dynamic characteristics

 $V_{SS} = 0 \text{ V}$; $T_{amb} = 25 \text{ °C}$; unless otherwise specified; for test circuit see <u>Figure 6</u>.

Symbol	Parameter	Conditions	V_{DD}		Extrapolation formula[1]	Min	Тур	Max	Unit
t _{PHL}	HIGH to LOW	CP → Q0	5 V		78 ns + (0.55 ns/pF)C _L	-	105	210	ns
	propagation delay	see <u>Figure 5</u>	10 V		34 ns + (0.23 ns/pF)C _L	-	45	90	ns
			15 V		27 ns + (0.16 ns/pF)C _L	-	35	70	ns
		$Qn \rightarrow Qn + 1$	5 V	[2]	(0.55 ns/pF)C _L	-	35	70	ns
			10 V	[2]	(0.23 ns/pF)C _L	-	15	30	ns
			15 V	[2]	(0.16 ns/pF)C _L	-	10	20	ns
		$MR \to Qn$	5 V		63 ns + (0.55 ns/pF)C _L	-	90	180	ns
		see Figure 5	10 V		29 ns + (0.23 ns/pF)C _L	-	40	80	ns
			15 V		22 ns + (0.16 ns/pF)C _L	-	30	60	ns
t _{PLH}	LOW to HIGH	$ \overline{CP} \to Q0 $ see Figure 5	5 V		58 ns + (0.55 ns/pF)C _L	-	85	170	ns
	propagation delay		10 V		29 ns + (0.23 ns/pF)C _L	-	40	80	ns
			15 V		22 ns + (0.16 ns/pF)C _L	-	30	60	ns
		$Qn \rightarrow Qn + 1$	5 V	[2]	(0.55 ns/pF)C _L	-	35	70	ns
			10 V	[2]	(0.23 ns/pF)C _L	-	15	30	ns
			15 V	[2]	(0.16 ns/pF)C _L	-	10	20	ns
t _t	transition time	see Figure 5	5 V	[3]	10 ns + (1.00 ns/pF)C _L	-	60	120	ns
			10 V		9 ns + (0.42 ns/pF)C _L	-	30	60	ns
			15 V		6 ns + (0.28 ns/pF)C _L	-	20	40	ns

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 Table 6.
 Dynamic characteristics ...continued

 $V_{SS} = 0 \text{ V}$; $T_{amb} = 25 \text{ °C}$; unless otherwise specified; for test circuit see Figure 6.

Symbol	Parameter	Conditions	V_{DD}	Extrapolation formula[1]	Min	Тур	Max	Unit
t _W	pulse width	CP input HIGH;	5 V		50	25	-	ns
		minimum width; see Figure 5	10 V		30	15	-	ns
		see <u>Figure 5</u>	15 V		20	10	-	ns
		MR input HIGH;	5 V		40	20	-	ns
	minimum width; see Figure 5	10 V		30	15	-	ns	
		See <u>Figure 5</u>	15 V		20	10	-	ns
t _{rec}	recovery time	MR input;	5 V		40	20	-	ns
		see Figure 5	10 V		30	15	-	ns
			15 V		20	10	-	ns
f _{max}	f _{max} maximum frequency	CP input;	5 V		10	20	-	MHz
		see <u>Figure 5</u>	10 V		15	30	-	MHz
			15 V		25	50	-	MHz

^[1] The typical values of the propagation delay and transition times are calculated from the extrapolation formulas shown (C_L in pF).

Table 7. Dynamic power dissipation P_D

 P_D can be calculated from the formulas shown. $V_{SS} = 0$ V; $t_r = t_f \le 20$ ns; $T_{amb} = 25$ °C.

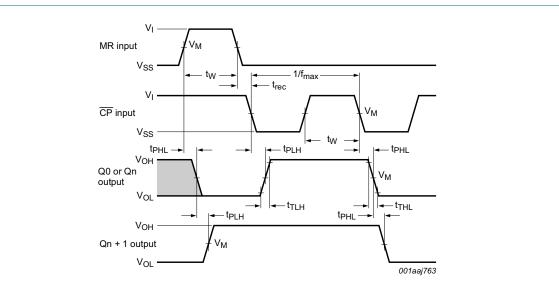
Symbol	Parameter	V_{DD}	Typical formula for P _D (μW)	where:
P_D	dynamic power	5 V	$P_D = 400 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2$	f_i = input frequency in MHz,
dissipation		10 V	$P_D = 2000 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2$	f _o = output frequency in MHz,
		15 V	$P_D = 5200 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2$	C_L = output load capacitance in pF,
				V_{DD} = supply voltage in V,
				$\Sigma(f_0 \times C_L)$ = sum of the outputs.

^[2] For loads other than 50 pF at the n^{th} output, use the slope given.

^[3] t_t is the same as t_{THL} and t_{TLH} .



11. Waveforms



Logic levels: V_{OL} and V_{OH} are typical output voltage levels that occur with the output load.

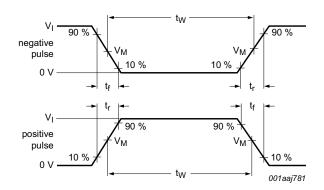
Transition times: transition time (t_t) = HIGH LOW (t_{THL}) or LOW HIGH (t_{TLH}) transition times.

Measurement points are given in Table 8, test circuit in Figure 6 and test data in Table 9

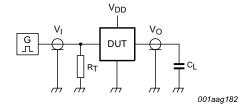
Fig 5. Waveforms showing propagation delays for MR to Qn and $\overline{\text{CP}}$ to Q0, minimum MR and $\overline{\text{CP}}$ pulse widths

Table 8. Measurement points

Supply voltage	Input	Output	
V_{DD}	V _I	V _M	V _M
5 V to 15 V	V _{DD} or V _{SS}	0.5V _{DD}	0.5V _{DD}



a. Input waveforms



b. Test circuit

Test data is given in Table 9.

Definitions test circuit:

DUT = Device Under Test;

 C_L = load capacitance, including the jig and probe capacitance;

 R_L = load resistance, which should be equal to the output impedance of the pulse generator.

Fig 6. Test circuit for measuring switching times

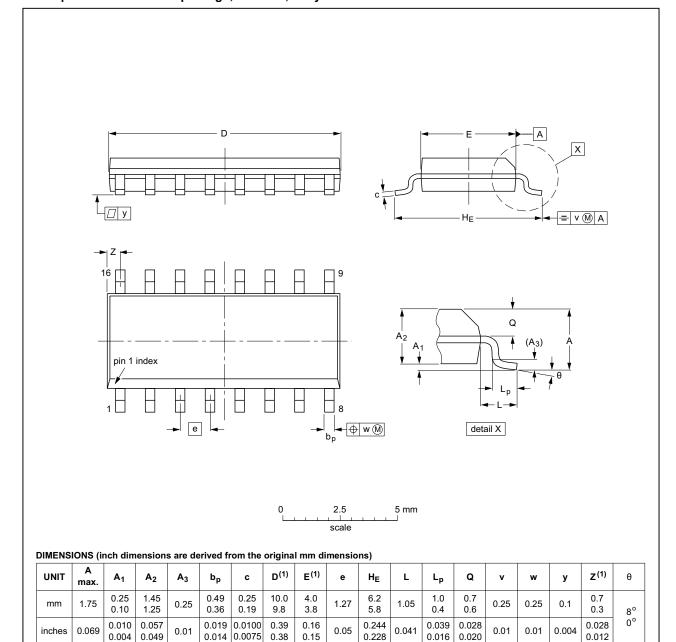
Table 9. Test data

Supply voltage	Input	Load		
V_{DD}	VI	t _r , t _f	CL	
5 V to 15 V	V _{SS} or V _{DD}	≤ 20 ns	50 pF	

12. Package outline

SO16: plastic small outline package; 16 leads; body width 3.9 mm

SOT109-1



Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE	REFERENCES				EUROPEAN	ISSUE DATE
VERSION	I IEC JEDEC JEITA			PROJECTION	ISSUE DATE	
SOT109-1	076E07	MS-012				99-12-27 03-02-19

Fig 7. Package outline SOT109-1 (SO16)

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13. Revision history

Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
HEF4040B v.9	20160323	Product data sheet	-	HEF4040B v.8
Modifications:	Type number HEF4040BP (SOT38-4) removed.			
HEF4040B v.8	20111117	Product data sheet	-	HEF4040B v.7
Modifications:	Legal pages updated.			
	Changes in "C	General description" and "Feat	ures and benefits".	
HEF4040B v.7	20111010	Product data sheet	-	HEF4040B v.6
HEF4040B v.6	20091125	Product data sheet	-	HEF4040B v.5
HEF4040B v.5	20090709	Product data sheet	-	HEF4040B v.4
HEF4040B v.4	20090304	Product data sheet	-	HEF4040B_CNV v.3
HEF4040B_CNV v.3	19950101	Product specification	-	HEF4040B_CNV v.2
HEF4040B_CNV v.2	19950101	Product specification	-	-

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14.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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